Issue	Classification

	n/Control	

10/661,862 Examiner

Hai L. Nguyen

Applicant(s)/Patent under Reexamination

NGUYEN ET AL.

Art Unit 2816

	ISSUE CLASSIFICATION											
	ORIGINAL					CROSS REFERENCE(S)						
	CLASS SUBCLASS			SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
	327			175	327	298						
U	INTERNATIONAL CLASSIFICATION			L CLASSIFICATION								
Н	0	3	К	3/017								
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Hai L. Nguyen
(Assistant Examiner)

meth Smith 3/7/6 (Legal Instruments Examiner) 3/7/6

3/05/2005 (Date) TIMOTHY P. CALLAHAN
SUPERVISORY PATENT EXAMINER
#ECHNOLOGY CENTER 2000

(Date)

Total Claims Allowed: 46

O.G. O.G. Print Claim(s) Print Fig.

Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. R.1.47 Original Original Original Original Original Original Original Final Final Final Final Final